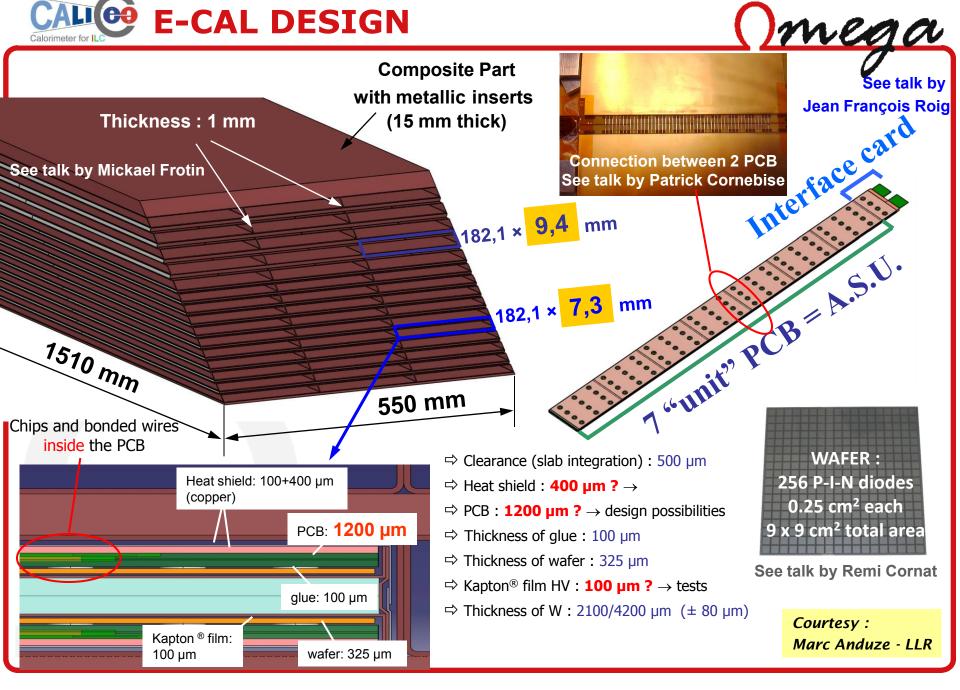
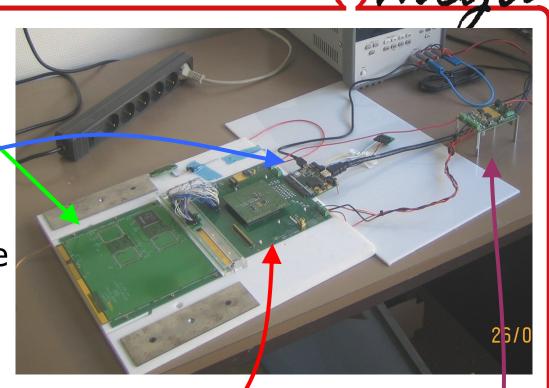


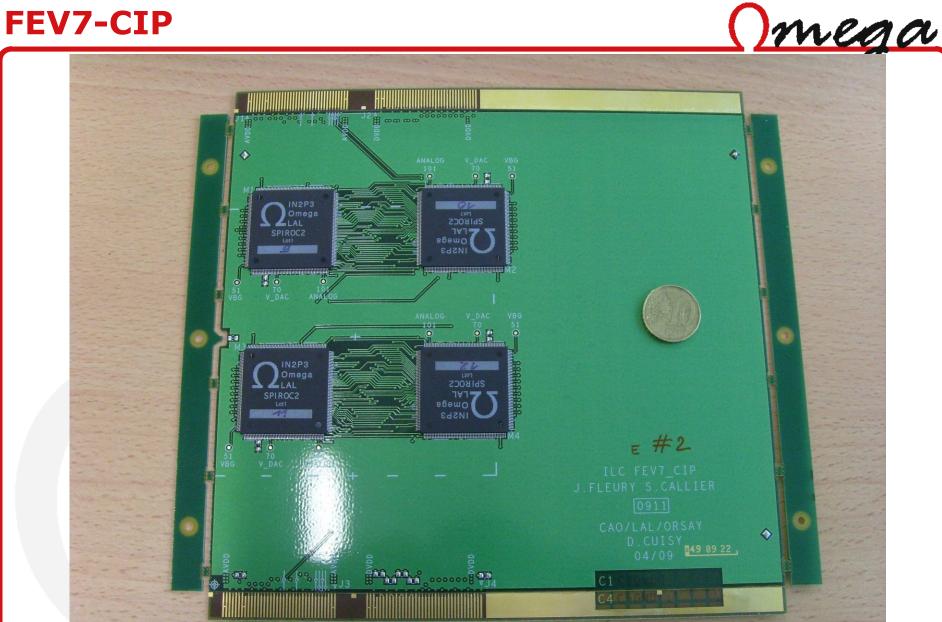
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### **FEV7s Test Bench**

- Test bench @ LLR using now FEV7-CIP (with 1 chip only)
- The DIF is ready to communicate with the adapter board (using HDMI link)
- The adapter board (SWEAT)
  - 2<sup>nd</sup> version for FEV7 is under study (compliant with cooling system) [See talk by JF Roig]
- The power management PCB (necessary due to SPIROC2 slow control loading issues)





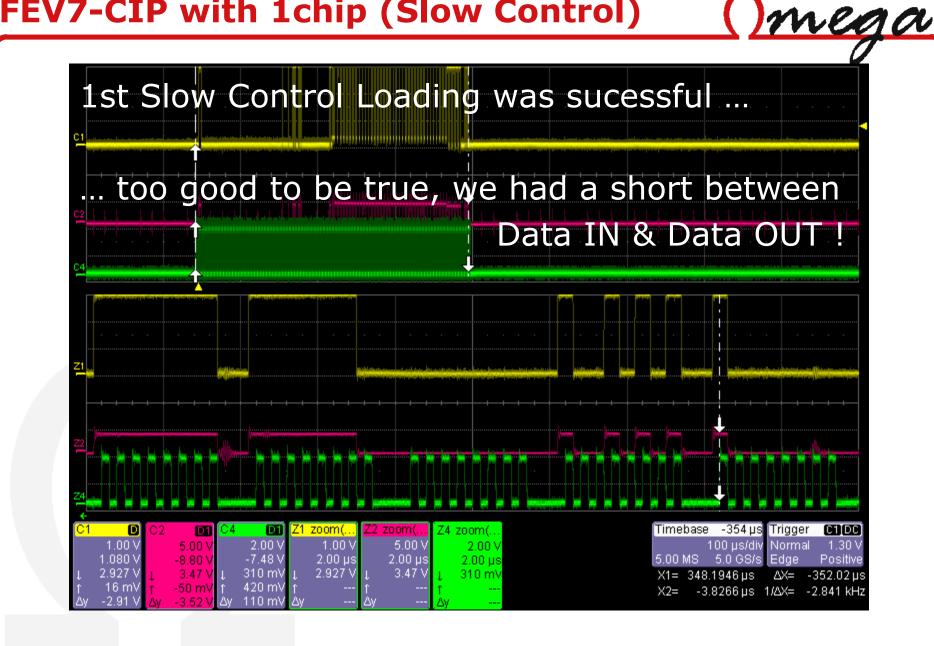
This FEV7-CIP will fit in the U structure

# **FEV7-CIP First Tests Setup**

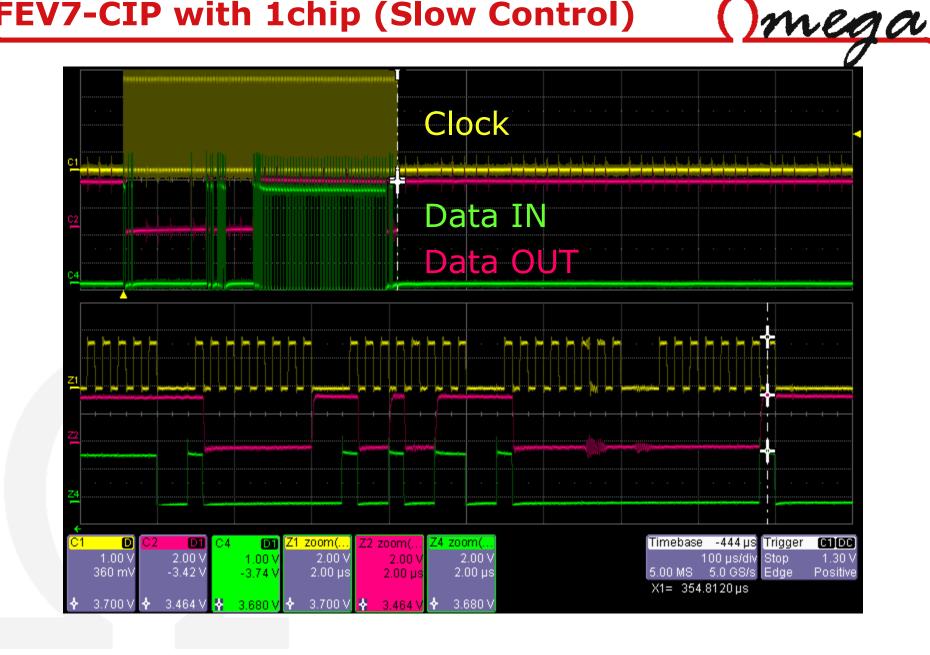


- Thanks to DIF TaskForce (Remi + Guillaume), we have 1 working DIF
- Slow Control files generated by SPIROC2 test software from 1 windows OS Notebook ...
- ... these files are copied to a Linux OS Computer...
- ... where data is afterward loaded in the memory of the DIF by the Python software and finally transferred to the FEV!
  - -> Not user friendly !!!

## **FEV7-CIP** with 1chip (Slow Control)



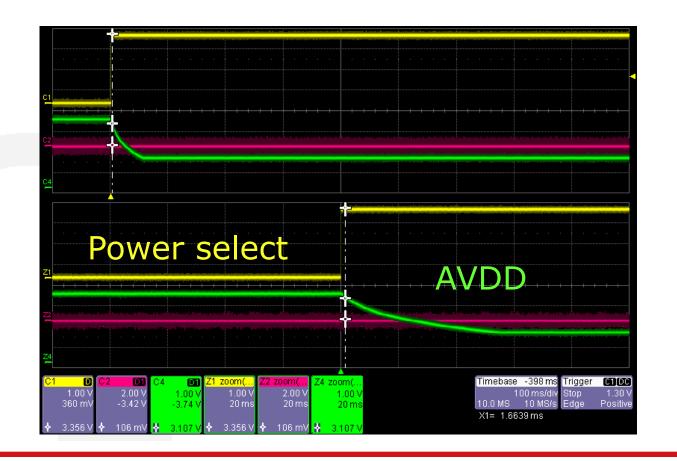
## **FEV7-CIP** with 1chip (Slow Control)



# **FEV7-CIP** with 1chip (Slow Control)



- The power switching needed by SPIROC2 works fine ... for 1 ASIC!
  - 60 ms needed to switch AVDD from 3.3V to 1.5V

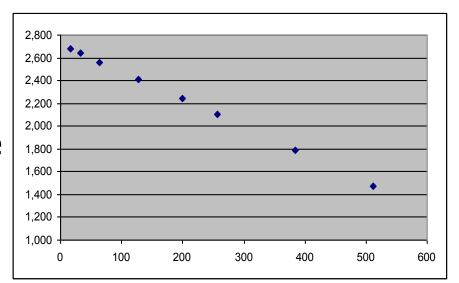


# **FEV7-CIP** with 1chip

Omega

- Bandgap stable @ 2.671V (GND on board = 0.13V)
- We played with POWER\_ON\_DAC command looking at Bandgap and DAC\_Threshold: OK!
- We then launched a COARSE linearity with the procedure described before ...

	<u> </u>
DAC Value	DAC Voltage (V)
16	2,680
32	2,643
64	2,563
128	2,412
200	2,239
256	2,100
384	1,787
512	1,470



#### FEV7-CIP with ...



- ...1 chip: We could work that way for the following tests (pedestal hold and conversion using external trigger) but nothing is automated !!!
- ...1 chip: How will we perform advanced test?
  - Calibration test!
  - Which software to control DAQ ? (user friendly requested)
    - Interraction between ASIC's slow control & test performed
  - Who will do that ? (volunteers ?)
- ...4 or more chips: How to proceed for the slow control generation? GUI? Automated tests?
  - 80% of the parameters will be identical
  - Chip ID NEED to be different for each devices!
  - Some other parameters can be tuned individually ...

## FEV7-COB1/2

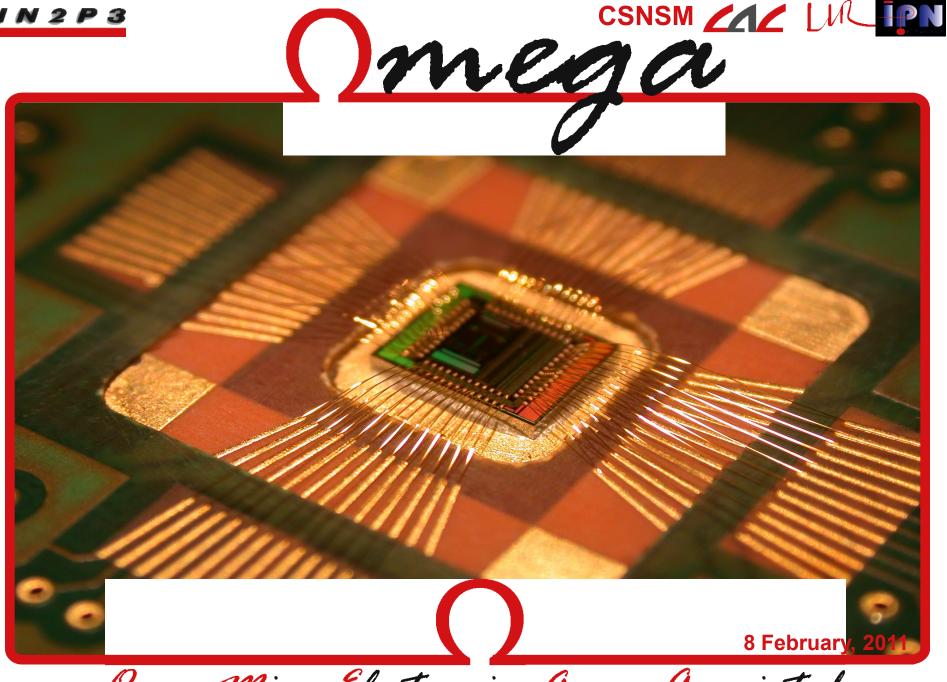


- For test with FEV7-COB / FEV7-COB2, debug will be even harder due to bonding on PCB!
- Same remark for FEV8 board, which SHOULD/MIGHT be a Chip-On-Board version!
- Test with more A.S.U. connected together (up to 7)
- Need to ask RPC/µmegas DHCAL and AHCAL people for they thought, and use it as a starting point

# **Summary**



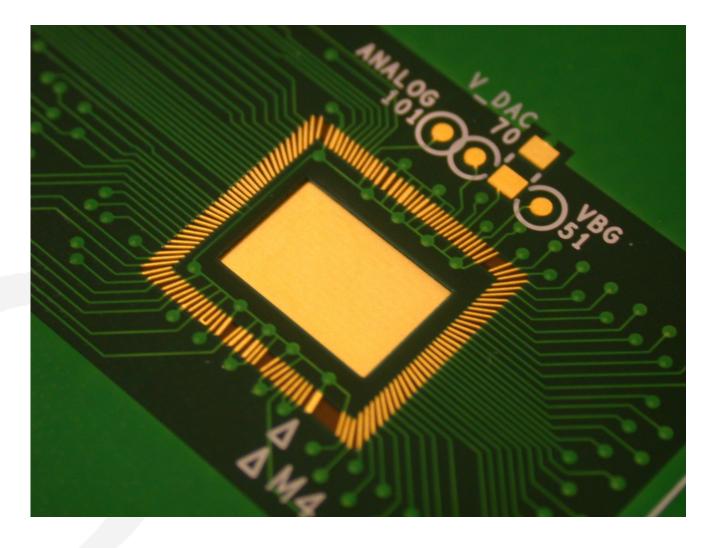
- Assuming that :
  - FEV8 board will be COB versions
  - In continuous mode, 1 SKIROC2 consumes 100mA
  - Each A.S.U. has 16 SKIROC2 chips
  - 1 fully equipped long SLAB <u>would</u> require more than 10A if not power pulsed
    - Test Beam? Interconnections? Adapter Board power supply?
- Now, FEV7 tests have started, great!
- However, I fear that this could be very time consuming for non optimized results unless we solve the "environment" (GUI software/slow control/data analysis) issue



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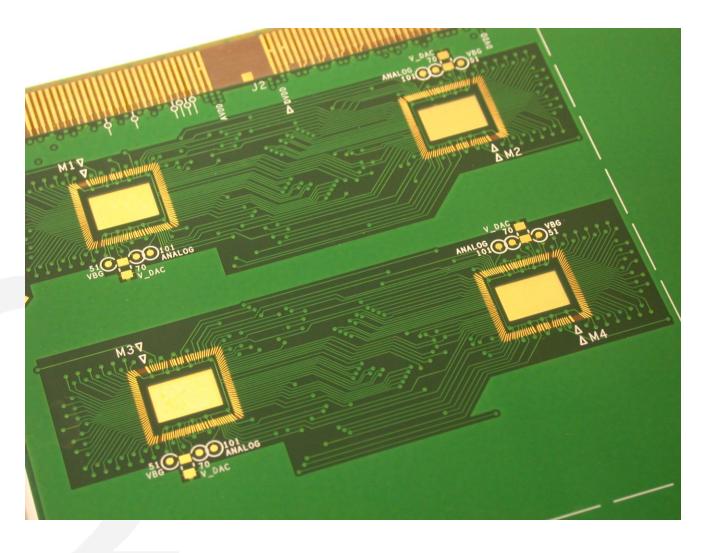
## **FEV7-COB**





## **FEV7-COB**





## FEV7-COB2



